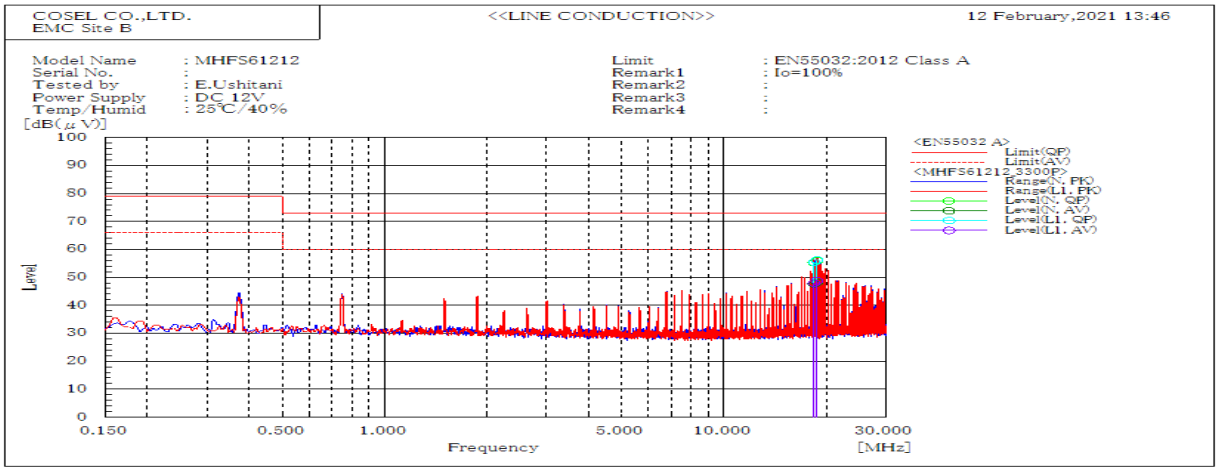
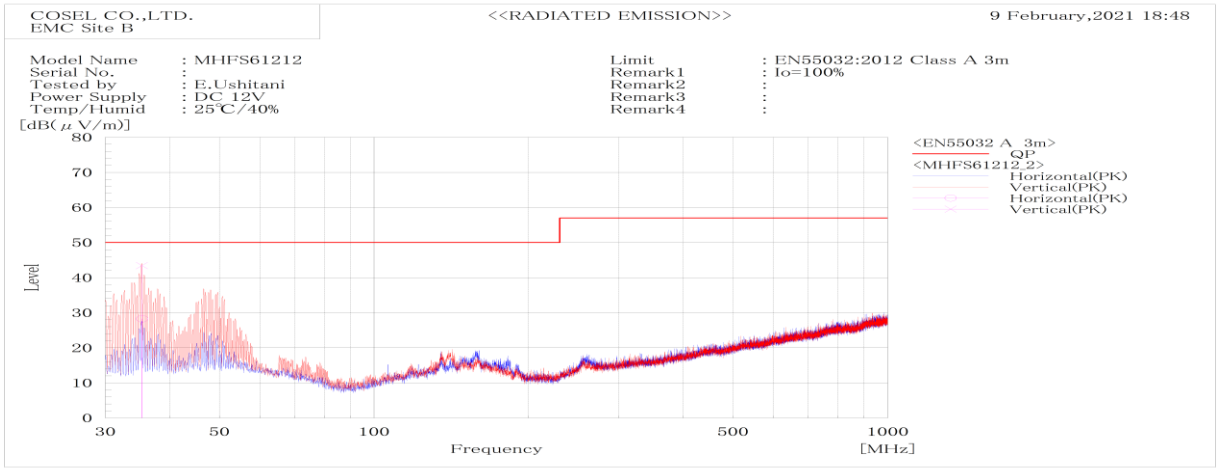
参考資料

COSEL

DATA SHEET		Date	05-Nov-21
Model	MHFS61212	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
18.791	L1	56.2	48.8	73	60	16.8	11.2	Pass	
18.415	L1	55.4	47.9	73	60	17.6	12.1	Pass	
18.784	N	56	48.2	73	60	17	11.8	Pass	
18.408	N	55.3	47.7	73	60	17.7	12.3	Pass	

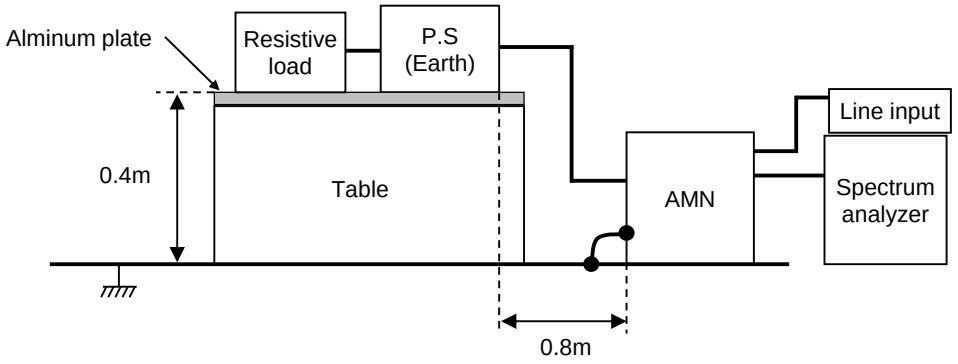


Frequency MHz	Polarization	Stability	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
35.356	H	Stable	28.3	50	21.7	Pass	101.5	23.5	
35.344	V	Stable	43.5	50	6.5	Pass	100	290.8	

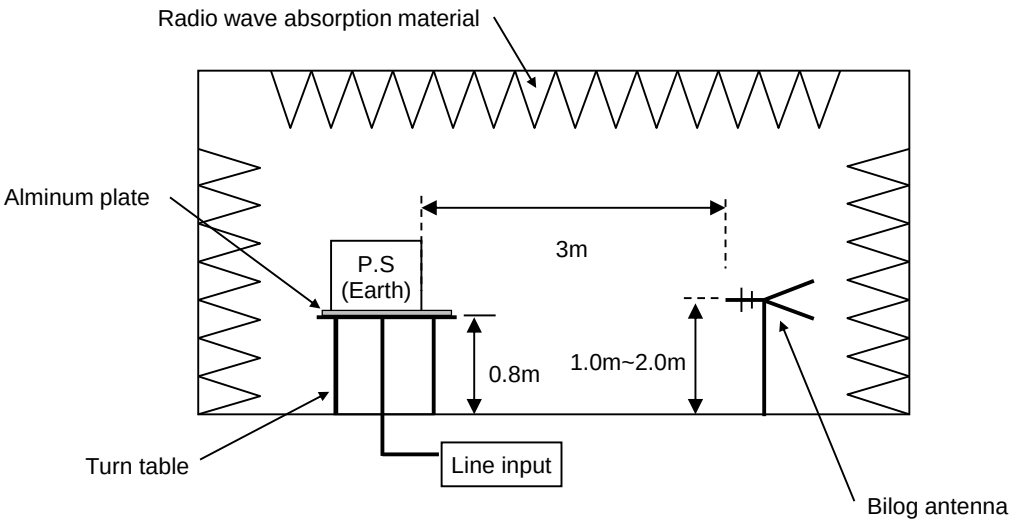
COSEL

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission



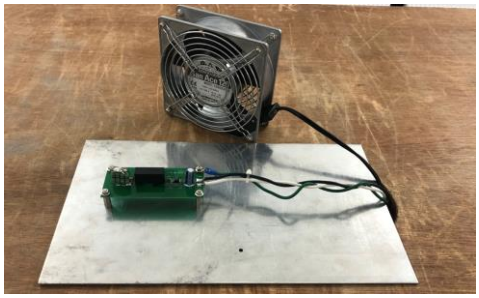
Conditions

Test : EMI
Model Name : MHFS6□□

○Photographs of Test Set-Up

LINE CONDUCTION

RADIATED EMISSION



○Testing circuitry

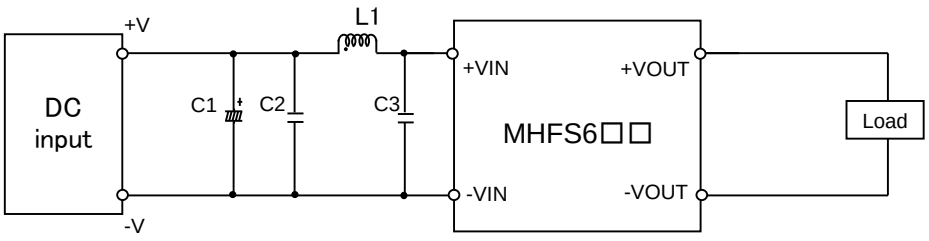


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100μF Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	–
	MHFS648□□	–
C2 :	MHFS612□□	25V 10μF Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7μF Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2μF Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10μF Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7μF Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2μF Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2μH Inductor(LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10μH Inductor(LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22μH Inductor(LQH5BPN220MT0 MURATA MANUFACTURING)